This index covers all technical items that appeared in this periodical during 1985, and items from prior years that were commented upon or corrected in 1985. The index is divided into an Author Index and a Subject Index, both arranged alphabetically.

The Author Index contains the primary entry for each item; this entry is listed under the name of the first author and includes coauthor names, title, location of the item, and notice of corrections and comments if any. Cross-references are given from each coauthor name to the name of the corresponding first author. The location of the item is specified by the journal name (abbreviated), year, month, and inclusive pages.

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